

# CALL FOR PAPERS



**ABSTRACT DEADLINE: NOVEMBER 15, 1992**

## SYMPOSIA

### **A: AMORPHOUS SILICON TECHNOLOGY - 1993**

E. Schiff, Syracuse University, (315) 443-3908, FAX (315) 443-9103; Malcolm J. Thompson, Xerox PARC, (415) 812-4561, FAX (415) 812-4919; Peter G. LeComber, University of Dundee, United Kingdom, (44) 382-23181, FAX (44) 382-25413; Arun Madan, MV-Systems, Inc., (303) 526-9016, FAX (303) 526-1408; K. Tanaka, Electrotechnical Laboratory, Japan, (81) 298-58-5488, FAX (81) 298-58-5403

### **B: SILICON-BASED OPTOELECTRONIC MATERIALS**

R.T. Collins, IBM T.J. Watson Research Center, (914) 945-3134, FAX (914) 945-2536; M.A. Tischler, IBM T.J. Watson Research Center, (914) 945-2891, FAX (914) 945-2141; G. Abstreiter, Technische Universität München, Germany, (49) 89-3209-2770, FAX (49) 89-3206-620; M.L. Thewalt, Simon Fraser University, British Columbia, (604) 291-3384, FAX (604) 291-3592

### **C1: II-VI COMPOUND SEMICONDUCTOR PHOTOVOLTAIC TECHNOLOGY**

R. Noufi, National Renewable Energy Laboratory, (303) 231-7310, FAX (303) 231-1381; K.W. Mitchell, Siemens Solar Industries, (805) 388-6511, FAX (805) 388-6580; R.W. Birkmire, University of Delaware, (302) 831-6231, FAX (302) 831-6226

### **C2: INFRARED DETECTORS - MATERIALS, PROCESSING, AND DEVICES**

Ami Appelbaum, Semi-Conductor Devices, Israel, (972) 490-6643, FAX (972) 490-6626; L. Ralph Dawson, Sandia National Laboratories, (505) 845-8920, FAX (505) 844-1197

### **D1: III-V ELECTRONIC AND PHOTONIC DEVICE FABRICATION AND PERFORMANCE**

K.S. Jones, University of Florida, (904) 392-9872, FAX (904) 392-6359; S.J. Pearson, AT&T Bell Laboratories, (908) 582-4757, FAX (908) 582-5917; H. Kanber, Hughes Aircraft Company, (310) 517-6408, FAX (310) 517-5657

### **D2: LOW-TEMPERATURE-GROWN AND HIGHLY NON-STOICHIOMETRIC GaAs AND RELATED MATERIALS**

Gerald Witt, Air Force Office of Scientific Research, (202) 767-4931, FAX (202) 767-4986; David Look, Wright State University, (513) 255-1725, FAX (513) 255-3374; Michael Melloch, Purdue University, (317) 494-3528, FAX (317) 494-6440; Frank W. Smith, MIT/Lincoln Laboratory, (617) 981-4485, FAX (617) 981-3867

### **E: RARE-EARTH DOPED SEMICONDUCTORS**

Gernot S. Pomrenke, Air Force Office of Scientific Research, (202) 767-4931, FAX (202) 767-4986; Paul B. Klein, Naval Research Laboratory, (202) 767-3692, FAX (202) 767-1165; Dietrich W. Langer, University of Pittsburgh, (412) 624-9663, FAX (412) 624-1108

### **F: SEMICONDUCTORS FOR ROOM-TEMPERATURE RADIATION DETECTOR APPLICATIONS**

Ralph B. James, Sandia National Laboratories, (510) 294-2782, FAX (510) 294-3231; T.E. Schlesinger, Carnegie-Mellon University, (412) 268-8728, FAX (412) 268-2860; Paul Siffert, Laboratoire PHASE/CRN, France, (33) 88-286543, FAX (33) 88-230990; Larry Franks, EG&G Energy Measurements, (805) 681-2206, FAX (805) 967-5884

### **G: RAPID THERMAL AND INTEGRATED PROCESSING**

Jeffrey C. Gelpy, Peak Systems, Inc., (508) 535-6997, FAX (508) 535-7079; Jimmie J. Wortman, North Carolina State University, (919) 515-5255, FAX (919) 515-3027; J. Kiefer Elliott, SEMATECH, (512) 356-3570, FAX (512) 356-3083; Atul Ajmera, IBM Technology Products, (914) 892-3740, FAX (914) 892-4604

### **H: POLYMER/INORGANIC INTERFACES**

Robert L. Opila, AT&T Bell Laboratories, (908) 582-3390, FAX (908) 582-2226, RLO@CLOCKWISE.ATT.COM; F. James Boerio, University of Cincinnati, (513) 556-3111, FAX (513) 556-2569; Alvin W. Czanderna, National Renewable Energy Laboratory (NREL), (303) 231-1240, FAX (303) 231-1381

### **I: HIGH-PERFORMANCE POLYMERS AND POLYMER MATRIX COMPOSITES**

Ronald K. Eby, University of Akron, (216) 972-7539, FAX (216) 972-5290; Robert C. Evers, USAF Wright Laboratories, (513) 255-9161, FAX (513) 255-9157; Doug Wilson, BP Chemicals (Hitco), Inc., (714) 755-7233, FAX (714) 755-7298; Michael A. Meador, NASA Lewis Research Center, (216) 433-9518, FAX (216) 433-8011

### **J: ORGANIC MATERIALS FOR NONLINEAR OPTICAL APPLICATIONS**

Christopher R. Moylan, IBM Almaden Research Center, (408) 927-1287, FAX (408) 927-2100; Richard S. Lytel, Lockheed Missiles & Space Company, (415) 424-2363, FAX (415) 424-3115; Seth R. Marder, California Institute of Technology, (818) 397-2829, FAX (818) 449-4159

### **K: MATERIALS ASPECTS OF X-RAY LITHOGRAPHY**

George K. Celler, AT&T Bell Laboratories, (908) 582-2861, FAX (908) 582-2950, GKCC@PHYSICS.ATT.COM; Juan R. Maldonado, IBM, (919) 894-6765, FAX (914) 892-6025

### **L: APPLICATIONS OF SYNCHROTRON RADIATION TECHNIQUES TO MATERIALS SCIENCE**

Dale L. Perry, Lawrence Berkeley Laboratory, (510) 486-4819, FAX (510) 486-5799; Neal Shinn, Sandia National Laboratories, (505) 844-5457, FAX (505) 844-5470; Roger Stockbauer, Louisiana State University, (504) 388-1263, FAX (504) 388-5855; Kevin D'Amico, X-Ray Analytics, Ltd., (516) 282-2065, FAX (516) 282-5239; Louis Terminello, Lawrence Livermore National Laboratory, (510) 423-7956, FAX (510) 423-7040

## **M1: THIN FILMS - STRESSES AND MECHANICAL PROPERTIES IV**

Paul H. Townsend, Dow Chemical Company, (517) 636-8120, FAX (517) 636-6558; Che-Yu Li, Cornell University, (607) 255-4349, FAX (607) 255-2365; John Sanchez, Max-Planck-Institut für Metallforschung, Germany, (49) 711-2095-215, FAX (49) 711-2095-250; Timothy P. Weihs, Lawrence Livermore National Laboratory, (510) 422-1540, FAX (510) 422-2118

## **M2: MATERIALS RELIABILITY IN MICROELECTRONICS III**

Ken Rodbell, IBM T.J. Watson Research Center, (914) 945-1012, FAX (914) 945-2141, [RODBELL@WATSON.IBM.COM](mailto:RODBELL@WATSON.IBM.COM); William Filter, Sandia National Laboratories, (505) 844-3971, FAX (505) 844-2991; Paul Ho, University of Texas at Austin, (512) 471-8961, FAX (512) 471-9674, [HOP@UTXVM.CC.UTEXAS.EDU](mailto:HOP@UTXVM.CC.UTEXAS.EDU); Harold Frost, Dartmouth College, (603) 646-3444, FAX (603) 646-3856, [HAROLD.FROST@DARTMOUTH.EDU](mailto:HAROLD.FROST@DARTMOUTH.EDU)

## **N: FERROELECTRIC THIN FILMS III**

Edward R. Myers, National Semiconductor Corporation, (408) 721-2258, FAX (408) 736-8503; Bruce A. Tuttle, Sandia National Laboratories, (505) 845-8026, FAX (505) 844-2974; Seshu B. Desu, Virginia Polytechnic Institute, (703) 231-6820, FAX (703) 231-8919; Poul K. Larsen, Philips Research Laboratories, The Netherlands, (31) 40-743378, FAX (31) 40-743365

## **O: PHASE TRANSFORMATIONS IN THIN FILMS - THERMODYNAMICS AND KINETICS**

Michael Atzmon, University of Michigan, (313) 764-6888, FAX (313) 763-4540, [ATZMON@UM.CC.UMICH.EDU](mailto:ATZMON@UM.CC.UMICH.EDU); A. Lindsay Greer, University of Cambridge, United Kingdom, (44) 223-334308, FAX (44) 223-334748, [ALG13@PHX.CAM.AC.UK](mailto:ALG13@PHX.CAM.AC.UK); James M.E. Harper, IBM T.J. Watson Research Center, (914) 945-1663, FAX (914) 945-4015, [HARPERJ@WATSON.IBM.COM](mailto:HARPERJ@WATSON.IBM.COM); Matthew R. Libera, Stevens Institute of Technology, (201) 216-5259, FAX (201) 216-8306, [PTF\\_MLIBERA@VAXC.STEVENS-TECH.EDU](mailto:PTF_MLIBERA@VAXC.STEVENS-TECH.EDU)

## **P: COMMON THEMES AND MECHANISMS OF EPITAXIAL GROWTH**

Paul Fuoss, AT&T Bell Laboratories, (908) 582-4951, FAX (908) 582-7660, [FUOSS@PHYSICS.ATT.COM](mailto:FUOSS@PHYSICS.ATT.COM); Jeffrey Tsao, Sandia National Laboratories, (505) 844-7092, FAX (505) 844-8985; David W. Kisker, IBM T.J. Watson Research Center, (914) 945-1644, FAX (914) 945-2141, [DAVEK@WATSON.IBM.COM](mailto:DAVEK@WATSON.IBM.COM); Andrew Zangwill, Georgia Institute of Technology, (404) 894-7333, FAX (404) 853-9958, [ZANGWILL@ZANGLGATECH.EDU](mailto:ZANGWILL@ZANGLGATECH.EDU); Thomas F. Kuech, University of Wisconsin, Madison, (608) 263-2922, FAX (608) 262-5434, [KUECH@CHE31A.CHE.WISCEDU](mailto:KUECH@CHE31A.CHE.WISCEDU)

## **Q1: MAGNETIC ULTRATHIN FILMS, MULTILAYERS AND SURFACES**

C. Chappert, IBM Research Almaden Research Center, (408) 927-2373, FAX (408) 927-2100; R. Clarke, University of Michigan, (313) 764-4466, FAX (313) 764-2193; R.F.C. Farrow, IBM Almaden Research Center, (408) 927-2389, FAX (408) 927-2100; P. Grünberg, Forschungszentrum Jülich, Germany, (49) 24-61613288, FAX (49) 24-61612410; B.T. Jonker, Naval Research Laboratory, (202) 767-3603, FAX (202) 767-1697; Kannan M. Krishnan, Lawrence Berkeley Laboratory, (510) 486-4614, FAX (510) 486-5888; Shigeru Tsunashima, Nagoya University, Japan, (81) 52-781-5111, FAX (81) 52-781-8143

## **Q2: MAGNETIC INTERFACES - PHYSICS AND CHARACTERIZATION**

Ernesto E. Marinero, IBM Almaden Research Center, (408) 927-2077, FAX (408) 927-3025; Takeshi Egami, University of Pennsylvania, (215) 898-5138, FAX (215) 898-8296; Carl Rau, Rice University, (713) 285-5417, FAX (713) 527-9033; Scott A. Chambers, Boeing High Technology Center, (206) 865-3071, FAX (206) 865-2888

## **R: JOINING AND ADHESION OF ADVANCED INORGANIC MATERIALS**

A.H. Carim, Pennsylvania State University, (814) 863-4296, FAX (814) 865-2917; D.S. Schwartz, McDonnell Douglas Research Laboratories, (314) 232-6835, FAX (314) 777-1328; R.S. Silbergliitt, Technology Assessment & Transfer, Inc., (301) 261-8373, FAX (410) 224-4678; R.E. Loezman, Sandia National Laboratories, (505) 844-2222, FAX (505) 846-5064

## **S: FULLERENES AND RELATED MATERIALS**

Peter Stephens, SUNY-Stony Brook, (516) 632-8156, FAX (516) 632-8176, [PSTEPHENS@SBCCMAIL.BITNET](mailto:PSTEPHENS@SBCCMAIL.BITNET); Yohji Achiba, Tokyo Metropolitan University, Japan, (81) 426-772534, FAX (81) 426-772525; Rodney S. Ruoff, SRI International, (415) 859-2667, FAX (415) 859-6196, [RUOFF@MPLVAX.SRI.COM](mailto:RUOFF@MPLVAX.SRI.COM); J. Gerard Lavin, DuPont Fibers, (302) 695-2892, FAX (302) 695-1717, [LAVINJG@CSOC.DNET.DUPONT.COM](mailto:LAVINJG@CSOC.DNET.DUPONT.COM)

## **T: MATERIALS ISSUES IN HIGH-TEMPERATURE SUPERCONDUCTIVITY**

Subhash L. Shindé, IBM Corporation, (914) 894-4366, FAX (914) 892-6256; Susan E. Babcock, University of Wisconsin-Madison, (608) 263-5696, FAX (608) 263-1087; John Talvacchio, Westinghouse STC, (412) 256-1437, FAX (412) 256-1348; Theodore H. Geballe, Stanford University, (415) 723-0215, FAX (415) 725-2189

## **U: MECHANISMS OF DEFORMATION AND FAILURE IN ROCKS AND CERAMICS**

Joanne T. Fredrich, Terra Tek, Inc., (801) 584-2487, FAX (801) 584-2432; Andreas K. Kronenberg, Texas A&M University, (409) 845-0132, FAX (409) 845-6780; David J. Green, Pennsylvania State University, (814) 865-4992, FAX (814) 865-2917; Reid F. Cooper, University of Wisconsin-Madison, (608) 262-1133, FAX (608) 262-8353

## **V: HYDROXYAPATITE AND RELATED COMPOUNDS**

Paul W. Brown, Pennsylvania State University, (814) 865-5352, FAX (814) 865-2326; Brent Constantz, Norian Corporation, (415) 968-5566, FAX (415) 968-5742

## **W: THEORY OF MATERIALS PROPERTIES**

Juan M. Sánchez, University of Texas, Austin, (512) 471-0091, FAX (512) 471-6713, [SANCHEZ@ALPHA.ME.UTEXAS.EDU](mailto:SANCHEZ@ALPHA.ME.UTEXAS.EDU); Robb M. Thomson, NIST, (301) 975-5665, FAX (301) 926-8349, [ROBB@PHLOGISTON.NIST.GOV](mailto:ROBB@PHLOGISTON.NIST.GOV); R.E. Watson, Brookhaven National Laboratory, (516) 282-3788, FAX (516) 282-2918

## **X: FRONTIERS OF MATERIALS RESEARCH**

Rustum Roy, Pennsylvania State University, (814) 865-3421, FAX (814) 865-2326; Martin L. Green, AT&T Bell Laboratories, (908) 582-5310, FAX (908) 582-7660; Merrilea J. Mayo, Pennsylvania State University, (814) 863-7330, FAX (814) 865-2917; Stephen M. Shapiro, Brookhaven National Laboratory, (516) 282-3822, FAX (516) 282-2918

## **Y: SURFACE CHEMICAL CLEANING AND PASSIVATION FOR SEMICONDUCTOR PROCESSING**

Gregg S. Higashi, AT&T Bell Laboratories, (908) 582-5024, FAX (908) 582-4228; Eugene A. Irene, University of North Carolina, (919) 966-1652, FAX (919) 962-2388; Tadahiro Ohmi, Tohoku University, Japan, (81) 22-224-2649, FAX (81) 22-224-2549

For general meeting information, contact:



**MATERIALS RESEARCH SOCIETY**  
9800 McKnight Road, Pittsburgh, PA 15237  
FAX (412) 367-4373

## **MEETING CHAIRS**

Martin L. Green, AT&T Bell Laboratories, 600 Mountain Avenue, 7C-230, Murray Hill, NJ 07974, (908) 582-5310, FAX (908) 582-7660

Merrilea J. Mayo, Department of Materials Science and Engineering, Pennsylvania State University, Room 222, Steidle Building, University Park, PA 16802, (814) 863-7330, FAX (814) 865-2917

Stephen M. Shapiro, Physics Department, Brookhaven National Laboratory, Building 510B, Upton, NY 11973, (516) 282-3822, FAX (516) 282-2918